

Model QT-50/5601TSR

4 POINT PROBE sheet resistance measurement system



Quatek presents Four-Point Probe measurement system is consist of 5601TSR sheet resistance tester and QT50 manual test stage.

This system base on the Four Point Probe principle to measure the sheet resistance and resistivity. The sample could be wafer, ITO and other semiconductor materials. The dimension of sample could be square or circle. The machine is small, potable and easy operation. *Option: QT60 large manual test stage, QT70 auto test stage and ST-610A handheld probe.

Functional Performance: 5601TSR sheet resistance tester

Maximun Display:	150000(sheet resistance Ω/\square)/33000(normal resistance Ω)
Sampling Rate:	4 samples/sec
Display:	6 digits, LED dispaly
Overload Indication:	"00000" Flashing
Range selection:	Manual or Auto
Overload protection:	AC 330Vrms
Working voltage:	AC90V~264V, 50/60Hz<15VA
operating temperature:	0~50°C, RH \leq 80%
Communication interface:	RS232, RS485
Baud rate:	1200/2400/4800/9600/19200/38400/57600/115200
Dimension:	208x 91x 280mm

QT-50 manual test stage:

- Manual machines under pressure lever arm positioning function for detecting
- Needle pressure: Change the pressure by external additive weight 50~500g
- Dimension: 300x250x200mm
- Test stage size: Diameter 150mm , 6" wafer
- Weight: 7kg

Application:

- Solar photoelectric material
- Conductive polymeric material
- Transparent conducting films material
- ITO film
- Nano materials
- Micro molecule organic light emitting materials
- Biochip coating materials



QH-1026 Probe Spec:

- Probe spacings: 1mm*4
- Probe contact resistance: 150m Ω
- Probe pressure control among 45g \pm 20%
- Maximum current: 1000mA
- Needle head: rhodanized Sk4 High Carbon Steel
Circle needle head radii: 150 μ m
Tine needle head radii: <35 μ m; Angle 60°
- Weight: 53g
Dimension: 25x40x40mm

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we can supply kinds of test stage to be chosen

QT-60 Large manual test stage

- Wafer size: 8"~12"(300mm)
- Square size: 300x300mm
- Dimension: 250x320x170mm

QT-SW standard resistance Simulate wafer

- Range: 200m Ohm to 5K Ohm
- Customized value resistance
- Accuracy: 1%
- Standard diameter: 76mm
- Optional calibration report from calibration institution

ST-610A handheld probe

- Handheld style, pressing the grip to measure
- Suitable for different size of the sample
- Dimension: 107mm(H), 52mm (Diameter)
- Weight: 290g



ST-610A handheld probe



5601TSR sheet resistance test range

Range Selction	Measuring Range	Resolution	Current output	Accuracy
1500.00mΩ/□	0.01m~1500.00mΩ/□	10μΩ/□	DC 100mA	±0.05%±20digit
15000.0mΩ/□	0.1m~15000.0mΩ/□	100μΩ/□	DC 100mA	±0.02%±10digit
150.000Ω/□	0.001~150.000Ω/□	1mΩ/□	DC 100mA	
1500.00Ω/□	0.01~1500.00Ω/□	10mΩ/□	DC 10mA	
15.0000KΩ/□	0.1~15.0000KΩ/□	100mΩ/□	DC 1mA	
150.000KΩ/□	0.001K~150.000KΩ/□	1Ω/□	DC 100μA	
1500.00KΩ/□	0.01K~1500.00KΩ/□	10Ω/□	DC 10μA	
15000.0KΩ/□	0.1K~15000.0KΩ/□	100Ω/□	DC 1μA	±0.05%±20digit
150.000MΩ/□	0.001M~150.000MΩ/□	1KΩ/□	DC 100nA	